Hybrid 8j372 Traveler

May 26, 2000

1 Connectivity

Repairs on shorts:
Fixes for opens:

2 Chips

The following chips were assembled on this hybrid (in the order that the chips get read out):
Hybrid 8J372 has die: 169-027 169-032 169-033 169-034 170-045 170-049 170-050 170-053

3 Data Analysis Summary

The following summarizes the findings of the Burn-in data analysis program. The first chip in the readout name is numbered 0.

```
% Hybrid 8j372 classification info. Created 11:10:21 05/24/00

Hybrid 8j372 quality: fair
Chip classification: good good good good fair fair good good
Bad channels: none
Bad cells: none
Random bad capacitors (chip-cell-channel): 4-11-60 4-11-61 4-17-64
   4-34-20 4-7-87 5-2-126 5-22-113
Channels at pedestal needed for DCMS: 31.7 31.6 30.7 30.7 32.7 32.3 32.6 32.3
```

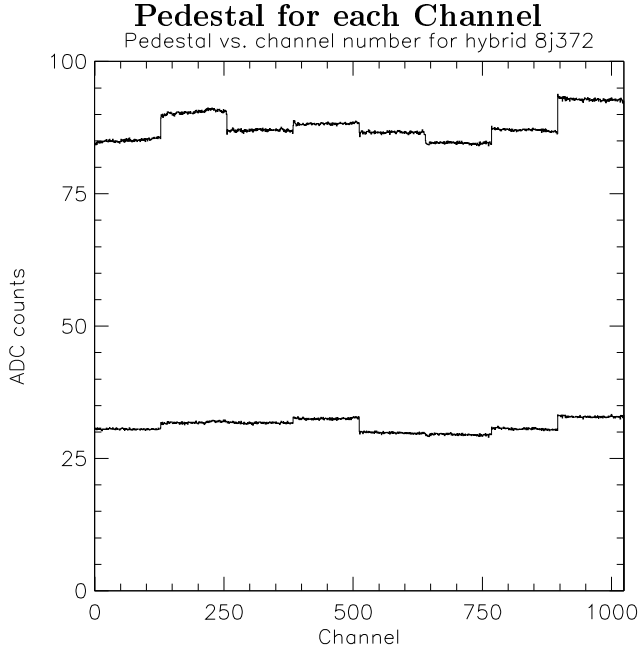
4 Comments

HV tested.

5 Pedestal

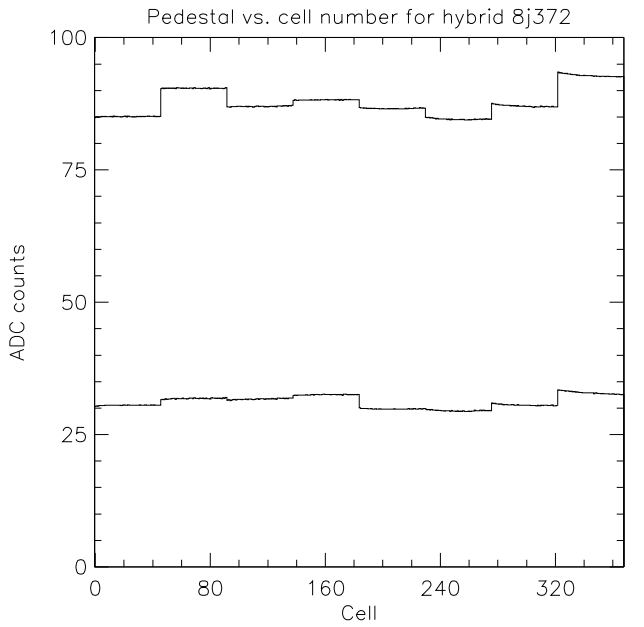
The following plot shows the pedestals vs. channel number with and without charge injection:

Pedestal for each Channel



The following plot shows the average pedestal vs. pipeline cell ID with and without charge injection. The x-axis is cell ID offset by 46 for each chip. Thus cell ID 5 for chip 1 is at x=5, chip 2 at x=51, chip 3 at x=97, etc.

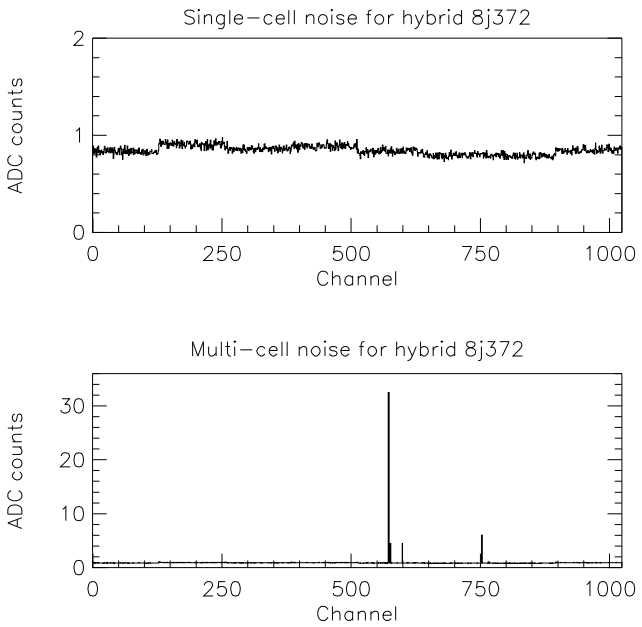
Pedestal vs. Pipeline Cell ID



6 Noise

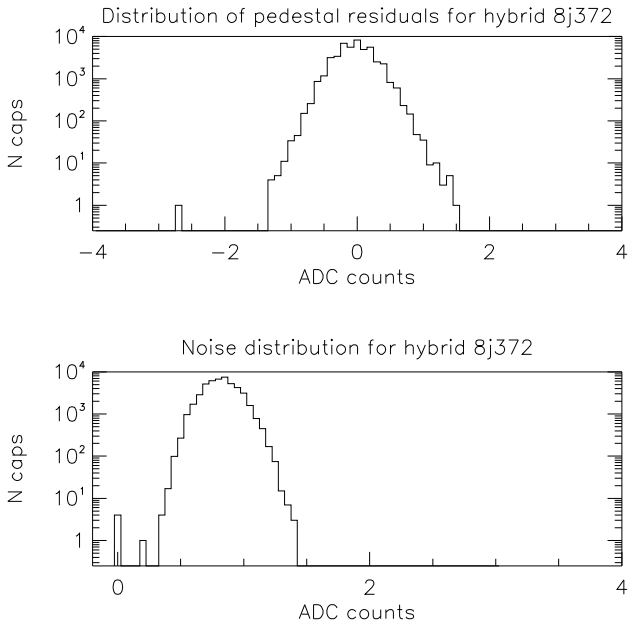
The following plots show the single-cell and multi-cell RMS noise:

RMS Noise

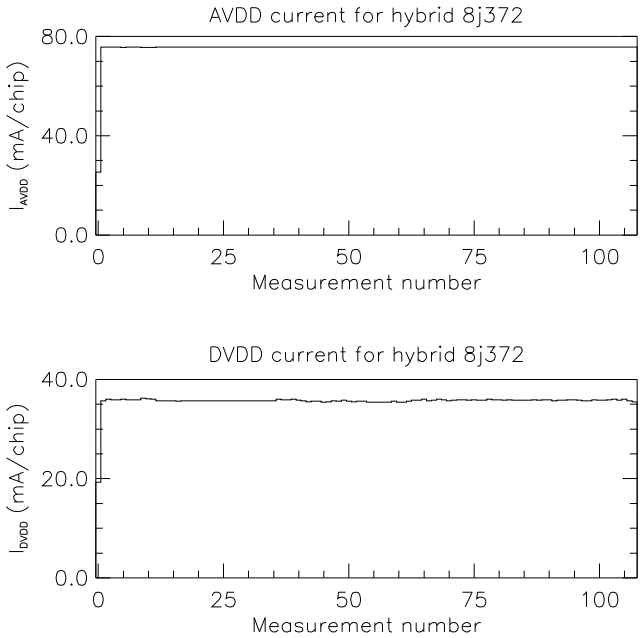


The following are histograms of the pedestal of each pipeline capacitor relative to the chip average (top); and the RMS noise of each capacitor (bottom):

Distribution of Pedestals and Noise



7 Currents

The following plots show the supply currents per chip as a function of measurment number. Currents are measured approximately every 10 minutes:

Supply Currents During Burn-in